

Notice of References Cited	Application/Control No. 10/565,653	Applicant(s)/Patent Under Reexamination KANAYA ET AL.	
	Examiner Keath T. Chen	Art Unit 1709	Page 1 of 1

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*	C	US-6,162,706	12-2000	Dutartre et al.	438/481
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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